

US006143997A

United States Patent [19]

Feng et al.

[11] Patent Number:

6,143,997

[45] **Date of Patent:**

Nov. 7, 2000

[54]	LOW ACTUATION VOLTAGE
	MICROELECTROMECHANICAL DEVICE
	AND METHOD OF MANUFACTURE

- [75] Inventors: Milton Feng, Champaign;
 - Shyh-Chiang Shen, Urbana, both of Ill.
- [73] Assignee: The Board of Trustees of the University of Illinois, Urbana, Ill.
 - Chiversity of Himois,
- [21] Appl. No.: 09/326,771
- [22] Filed: Jun. 4, 1999

- [56] References Cited

U.S. PATENT DOCUMENTS

4,959,515	9/1990	Zavracky et al	200/181
5,168,249	12/1992	Larson	333/81 A
5,258,591	11/1993	Buck	200/181
5,677,823	10/1997	Smith	361/234
6,046,659	4/2000	Loo et al	333/262

OTHER PUBLICATIONS

C.L. Goldsmith, Z. Yao, S. Eshelman, D. Denniston, "Performance of Low-Loss RF MEMS Capacitive Switches" *IEEE Microwave and Guides Wave Letters*, vol. 8, No. 8, Aug. 1988. (Date unknown).

N.S. Barker, G.M. Rebeiz, "Distributed MEMS True-Time Delay Phase Shifters and Wide-Bank Switches", *IEEE Transactions of Microwave Theory and Techniques*, vol. 46, No. 11, Nov. 1988, pp. 1881–1890.

E.R. Brown, "RF-MEMS Switches for Reconfigurable Integrated Circuits", *IEEE Transactions on Microwave Theory and Techniques*, vol. 46, No. 11, Nov. 1988, pp. 1868–1880.

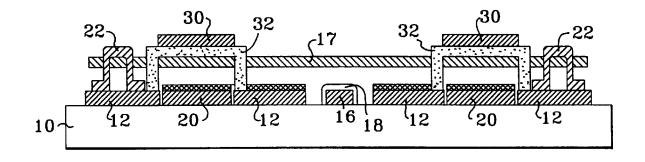
- J.J. Yao, M.F. Chang, "A Surface Micromachined Miniature Switch for Telecommunications Applications with Signal Frequencies from DC up to 4 GHz", IEEE conference paper, 1995. (No month).
- C. Goldsmith, T.H. Lin, B. Powers, W.R. Wu, B. Norvell, "Micromechanical Membrane Switches for Microwave Applications", *IEEE MTT-S Digest*, 1995, pp. 91–94. (No month).
- C. Goldsmith Z. Yao, S. Eshelman, D. Denniston, S. Chen, J. Ehmke, A. Malczewski, R. Richards, "Micromachining of RF Devices for Microwave Applications", Raytheon TI Systems Materials. (Date unknown).
- J.J. Yao, S.T. Park, J. DeNatale, "High Tuning—Ratio MEMS—Based Tunable Capacitors for RF Communications Applications", Solid State Sensor and Actuator Workshop, Hilton Head Island, South Carolina, Jun. 8, 1998.

Primary Examiner—Michael L. Gellner Assistant Examiner—Nhung Nguyen Attorney, Agent, or Firm—Greer, Burns & Crain, Ltd.

[57] ABSTRACT

A method and apparatus for controlling the flow of signals by selectively switching signals to ground and allowing signals to pass through a signal line based a position of a conductive pad. The switch contains waveguides including the signal line and at least one ground plane. The conductive pad responds to an actuation voltage to electrically connect the signal line and the ground planes when the metal pad is located in a relaxed position. When not located in the relaxed position, the switch breaks the connection to allow signals to flow through the signal line unimpeded. Brackets guide the pad as the pad moves between the relaxed position and a stimulated position due to the actuation voltage, without substantially deforming the conductive pad.

13 Claims, 10 Drawing Sheets



Nov. 7, 2000

Fig. 1A (PRIOR ART)

SWITCH UP (OFF STATE)

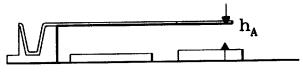
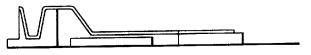


Fig. 1B (PRIOR ART)

SWITCH DOWN (ON STATE)



PULL-DOWN ELECTRODE

RF TRANSMISSION LINE

Fig. 2A (PRIOR ART)

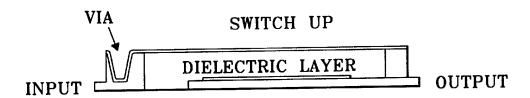
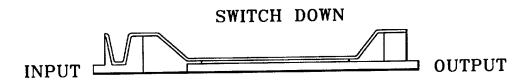
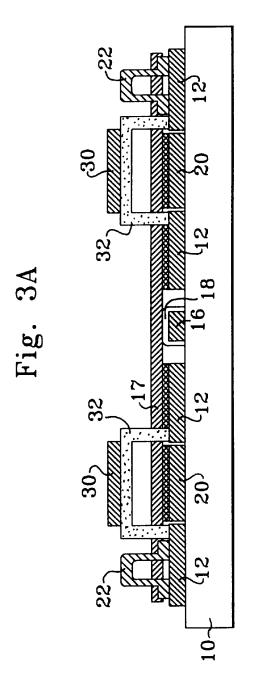
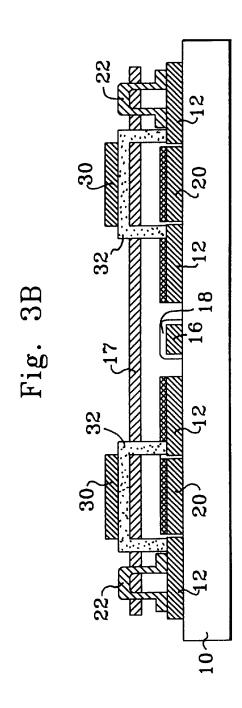


Fig. 2B (PRIOR ART)







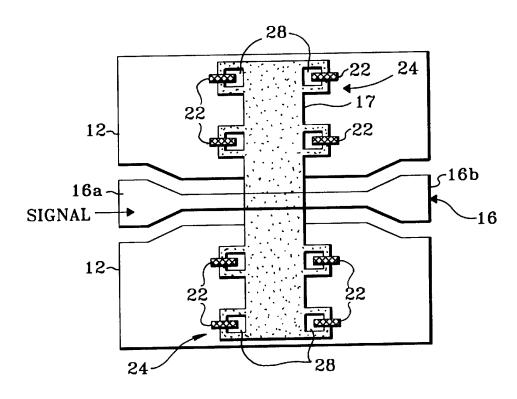
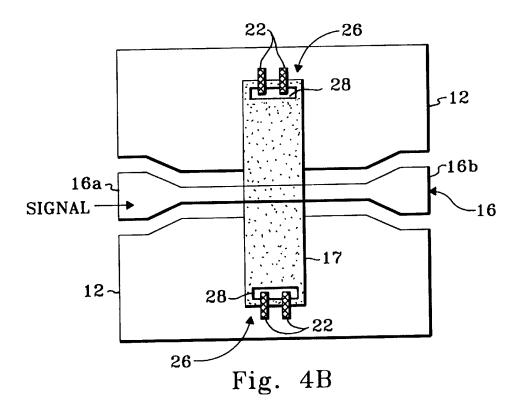


Fig. 4A



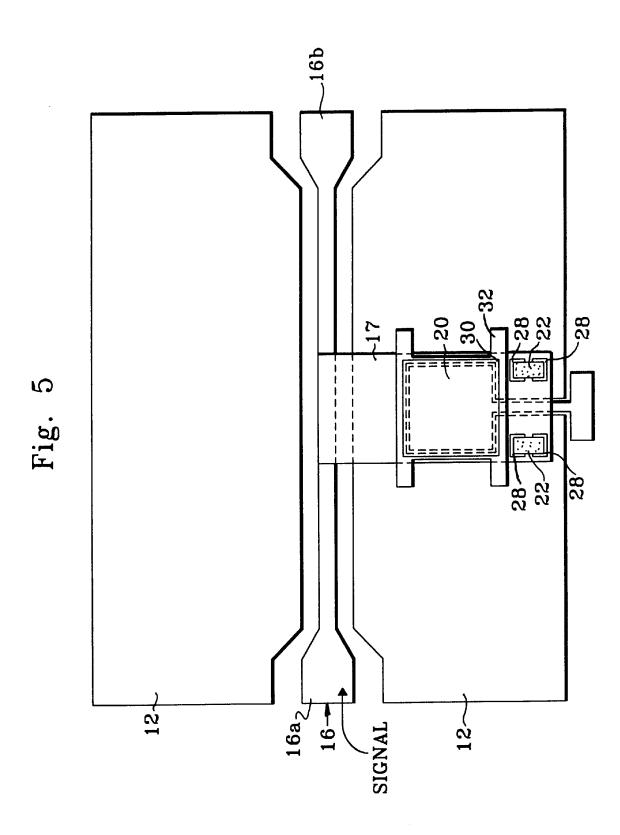


Fig. 6A

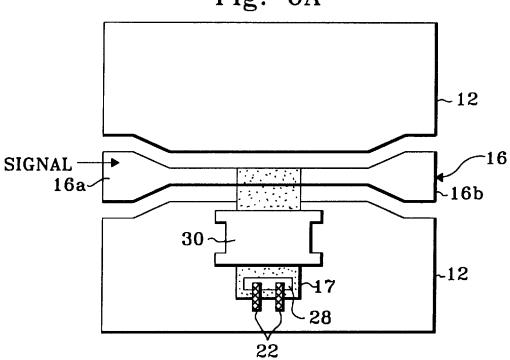
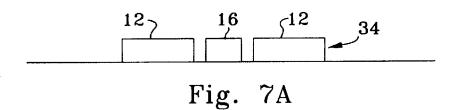
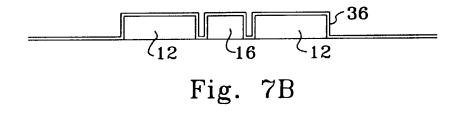


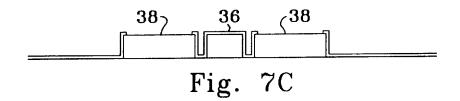
Fig. 6B

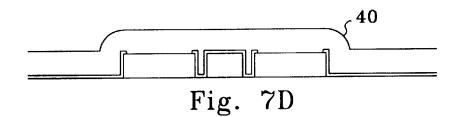
1216SIGNAL
16a

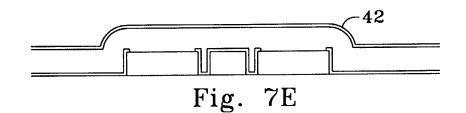
1222
16b











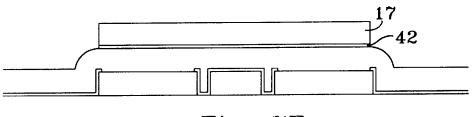
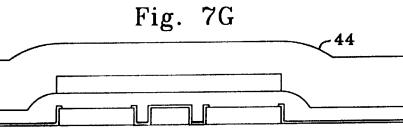
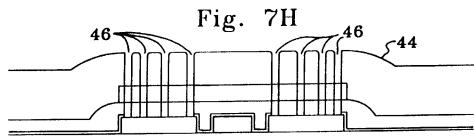
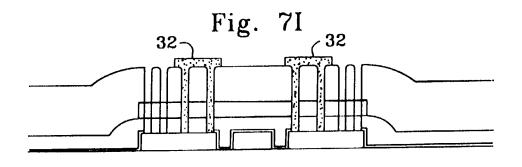
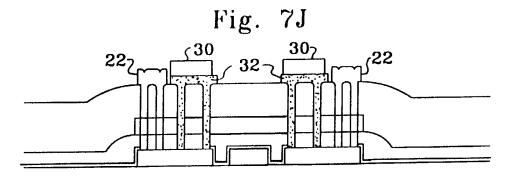


Fig. 7F









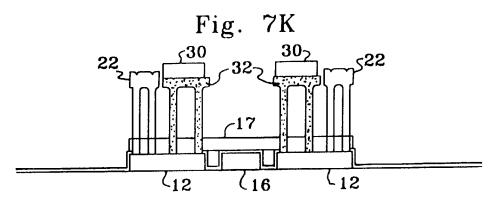
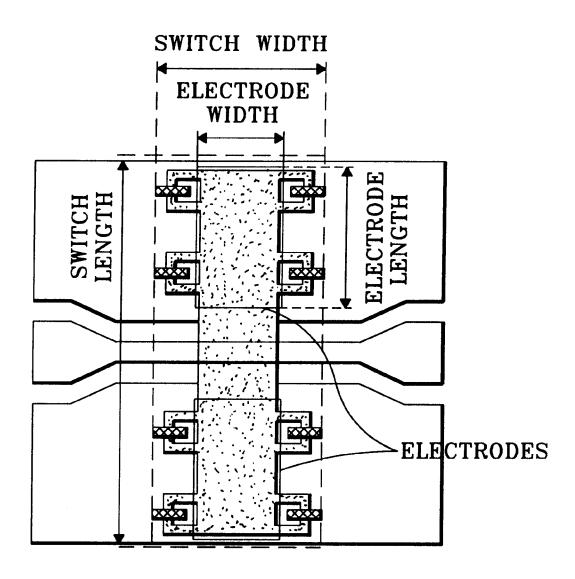


Fig. 8A

EVICE	DEVICE PARAMETER	PRESENT DIMENSION	MINIMUM POSSIBLE DIMENSION	MAXIMUM POSSIBLE DIMENSION	COMMENTS
WIDTH	SWITCH	100,150	0.1	1000	
(μm)	ELECTRODE	100,150	0.1	1000	NOT NECESSARIIA
LENGTH	SWITCH	450	ત્ય	1000	RECTANGULAR IN
(mm)	ELECTRODE	200,150,	જ	1000	SHAPE
		100,50			
IELEC THICK	DIELECTRIC LAYER THICKNESS $(\mu \mathrm{m})$	0	0	30	
EARAN TOP A ELECT	CLEARANCE BETWEEN TOP AND BOTTOM ELECTRODES (μm)	4	-	1000	

Fig. 8B



6,143,997

Nov. 7, 2000

	CANTILEVER (ROCKWELL)	MEMBRANE (TT)	HINGE TYPE (UIUC)
FREQUENCY (GHz)	4	$20 \sim 35$	50
RON (ก)	N/A	0.35	0.3
COFF (pF)	N/A	35	30
CUTOFF FREQUENCY (GHz)	N/A	0006<	>10,000
INSERTION LOSS (dB)	0.1	$0.14 \sim 0.17$	0.2
ISOLATION (dB)	20	$24 \sim 35$	30
CAPACITANCE RATIO	N/A	$80 \sim 110$	~100
SWITCHING SPEED (μs)	30	2>	8
SWITCHING VOLTAGE (V)	28	$30 \sim 50$	<3
SIZE (μm^2)	(200X200)X2	280X170	450 X 100 450 X 150

1

LOW ACTUATION VOLTAGE MICROELECTROMECHANICAL DEVICE AND METHOD OF MANUFACTURE

STATEMENT OF GOVERNMENT INTEREST

This invention was made with the assistance of the Defense Advanced Research Project Agency, under contract no. DARPA F30602-97-0328. The Government has certain rights in this invention.

FIELD OF THE INVENTION

The present invention generally concerns switches. More specifically, the present invention concerns microelectromechanical switches that are capable of switching at low actuation voltages.

BACKGROUND OF THE INVENTION

Switching operations are a fundamental part of many electrical, mechanical, and electromechanical applications. Microelectromechanical systems (MEMS) for switching applications have drawn much interest especially within the last few years. Products using MEMS technology are widespread in biomedical, aerospace, and communication systems. Recently, the MEMS applications for radio frequency (RF) communication systems have gained even more attention because of the MEMS's superior characteristics. RF MEMS have advantages over traditional active-device-based communication systems due to their low insertion loss, high linearity, and broad bandwidth performance.

Known MEMS utilize cantilever switch, membrane switch, and tunable capacitors structures. Such devices, however, encounter problems because their structure and innate material properties necessitate high actuation voltages to activate the switch. These MEMS devices require voltages ranging from 10 to 100 Volts. Such high voltage operation is far beyond standard Monolithic Microwave Integrated Circuit (MMIC) operation, which is around 5 Volts direct current (DC) biased operation.

Known cantilever and membrane switches are shown in FIGS. 1 and 2 in resting and (excited positions. FIG. 1A shows a cantilever switch in a resting position with a cantilever portion a distance h_A away from an RF transmission line to produce an off state since the distance h_A prevents current from flowing from the cantilever to the transmission line below it. To turn the switch on, a large switching voltage, typically in the order of 28 Volts, is necessary to overcome physical properties and bend the metal down to contact the RF transmission line (FIG. 1B). In the excited state, with the metal bent down, an electrical connection is produced between the cantilever portion and the transmission line. Thus, the cantilever switch is on when it exists in the excited state.

In addition, referring to FIGS. 2A and 2B, a known membrane switch is shown in a resting (FIG. 2A) and an 55 excited (FIG. 2B) position. When the membrane switch exists in the resting position, current is unable to flow from the membrane to an output pad and the switch is off. Like the cantilever switch, a high actuation voltage, typically 38 to 50 Volts, is necessary to deform the metal and activate the switch. In the excited state, the membrane is deformed to contact a dielectric layer on the output pad and thereby electrically connect the membrane to the output pad to turn the switch on. These designs also require a relatively high voltage

There is a need for an improved apparatus and method which addresses some or all of the aforementioned draw-

2

backs of known switches. Importantly, a new apparatus and method should overcome the need for high actuation voltages. In addition, the apparatus and method should overcome the limitations of traditional active-device-based Switches.

SUMMARY OF THE INVENTION

Such needs are met or exceeded by the present apparatus and method for switching. The present system controls the flow of a signal with a metal or other suitable conductive pad that moves freely up and down within brackets, without the need for deformation. The pad electrically grounds a signal when the pad is located in a relaxed position (contacts closed) and allows the signal to pass when located in a stimulated position (contacts open). The present invention includes electrodes that move the pad up and down with a low actuation voltage compared to known devices. The pad is not bent by the actuation voltage to make contact.

More specifically, in a preferred embodiment, the present invention controls the flow of signals by either shorting the signals to ground or allowing the signal pass through a signal line. The switch contains coplanar or other waveguides including the signal line and ground planes. The metal pad responds to an actuation voltage to electrically connect the signal line and the ground planes when the metal pad is in the relaxed position. When not located in the relaxed position, the switch allows signals to flow through the signal line unimpeded. Brackets guide the metal pad as the metal pad moves between the relaxed position and a stimulated position in response to the actuation voltage.

BRIEF DESCRIPTION OF THE DRAWINGS

Other features and advantages of the invention will be apparent to those skilled in the art with reference to the detailed description and the drawings, of which:

FIGS. 1A and 1B show a known cantilever switch shown in an off and on state respectively;

FIGS. 2A and 2B show a known membrane switch shown in an off and on state respectively;

FIG. 3A is a schematic cross-sectional side view of a preferred embodiment of a switch of the present invention in a pad down (contacts closed) position;

FIG. 3B is the same side view as FIG. 3A of the present invention in a pad up (contacts open) position;

FIG. 4A is a schematic top view showing hinge brackets of the present invention located on sides of a conductive pad;

FIG. 4B is a schematic top view showing hinge brackets of the present invention located on the ends of the conductive pad;

FIG. 5 is a schematic top view of an alternate embodiment of the hinge brackets of the present invention;

FIGS. 6A and 6B are schematic top views respectively showing one-sided and two-sided hinge structures of the present invention;

FIGS. 7A-7K are side views showing a process for manufacturing a switch of the present invention;

FIG. 8A is a table of possible dimensions for the switch of the present invention;

FIG. 8B is a schematic top view which identifies the dimensions shown in FIG. 8B; and

FIG. 9 is a table comparing the capabilities of known switches with the RF MEMS switch of the present invention.

3

TABLE OF ACRONYMS

This patent utilizes several acronyms. The following table is provided to aid the reader in understanding the acronyms:

C=Centigrade.

DC=direct current.

MEMS=microelectromechanical system.

MMIC=Monolithic Microwave Integrated Circuit.

PECVD=Plasma-Enhanced Chemical vapor deposition. RF=radio frequency.

DETAILED DESCRIPTION OF THE PREFERRED EMBODIMENTS

Generally, the present invention is an apparatus and 15 method for controlling the flow of signals. More specifically, the method and apparatus is a switch which is easy to produce and does not rely on the deformation of at least part of the system to activate the switch. Thus, the switch can be activated with a low voltage compared to known MEMS.

Referring now to the drawings, and particularly FIGS. 3A and 3B, the switch of the present invention includes a substrate base 10. Any type of substrate used in semiconductor fabrication can be applied to the present invention such as silicon, GaAs, InP, GaN, sapphire, quartz, glasses, and polymers. Upon the substrate base 10 are waveguides which include one or two ground planes 12 and a signal line 16. Any form of contacts used in integrated circuits can be used with the present invention, including coplanar waveguides and microstrip waveguides. For purposes of describing the invention, coplanar waveguides are shown.

The ground planes 12 pass signals, for example RF signals, from the signal line 16 to ground when the switch is in a relaxed (contacts closed) position, to produce an off state. While the present invention is described with regard to RF signals, it should be appreciated that other signals can be used, including low frequencies, millimeter-wave frequencies, and sub-millimeter-wave frequencies. The invention can be used for broad-band switching applications. To pass RF signals to ground, a conductive pad 17 is moveably positioned to contact both the signal line 16 and the ground planes 12 when the pad is in the relaxed position (FIG. 3A). The pad 17 is preferably made of metal, but can be made of any other suitable material. As shown with 45 arrows, the input RF signal enters from an input port 16a (shown best in FIGS. 4-6), flows through the pad 17, and then flows to ground by the ground planes 12. Therefore, no RF signal flows through the output port 16b and the switch exists in an off state. Thus, unlike known MEMS, an off state 50 (FIG. 3B). A clearance between the bottom electrodes 20 occurs when the metal pad 17 is in a relaxed (contacts closed) position.

Preferably, a thin dielectric layer 18 is positioned between the signal line 16 and the metal pad 17 to serve as a DC blocking capacitor. A zero dielectric thickness corresponds to a physical short in the switch. A non-zero dielectric thickness corresponds to a capacitively coupled shunt switch, i.e., effectively a low-pass filter or an RF short. Any type of dielectric material can be applied, such as silicon dioxide, silicon nitride, pyralene, polymers, glasses and the like. In addition, bottom electrodes 20 can be inserted between the pad 17 and ground planes 12, to enhance contact by attracting the pad 17 towards the waveguides.

Importantly, the pad 17 moves up and down freely with only the forces of gravity and air resistance to keep the metal 65 actuation electrodes. pad 17 down. To guide movement of the pad 17, the pad 17 is slidably positioned with brackets 22. Preferably, the

brackets 22 are placed atop the ground planes 12, and may be placed on any side of the metal pad 17. Referring to FIGS. 4A and 4B, brackets 22 are placed on sides 24 of the metal pad in FIG. 4A, and at ends 26 of the pad in FIG. 4B. As shown, each bracket 22 fits within an access hole 28 formed in the pad 17, to capture the pad 17 while allowing it to freely slide between its relaxed and excited positions.

FIG. 5 shows a device which is similar to the device of FIGS. 3A and 3B, but is one-sided. One or more brackets 22 can be fabricated within one or two access openings 28 formed on one end of the pad 17. Preferably, when two brackets and openings are used, as in FIG. 5, spacing between access holes is equal to or less than 25 μ m. For the hinge type switch of the present invention, two sacrificial layers each having a thickness of around 2 μ m are used. To remove the layers successfully, spacing between openings should be less than 15 μ m in all directions. It can be appreciated that the brackets 22 are designed with consideration given to a sacrificial layer removal capability and mechanical strength. Thus, the layer should be robust enough to contain the pad 17 while maintaining its physical integrity as the pad moves up and down, yet be easily removed by etching during a masking process described below.

Referring now to FIGS. 6A and 6B, bracket structures which secure the conductive pad 17 through a single opening 28 are shown applied to a one sided switch (FIG. 6A) and a two sided switch (FIG. 6B).

Referring again to FIGS. 3A and 3B, the switch system 30 includes top electrodes 30 which sit atop dielectric suspensions 32. Any suitable type of dielectric material can be used as the dielectric suspensions such as silicon dioxide, silicon nitride, pyralene, polymers, and glasses. Preferably, the dielectric suspensions 32 are positioned on the ground planes 12. Actuation voltage is applied alternately to the top electrode 30 and bottom electrode 20 to provide electrostatic force that causes the metal pad to move, preferably in an up and down direction. It should be appreciated, however, that an operation of the switch does not depend on the metal pad moving in the up and down direction. Since the minimum required electrostatic forces produced by the actuation voltage is approximately equal to the sum of the gravitation and the air friction forces on the pad 17, the applied voltage is much less than that necessary for the cantilever and membrane structures described above. Thus, a small actuation voltage, e.g., less than 3 Volts, for RF MEMS devices is achieved.

The conductive pad 17 is attracted upward when a small voltage, e.g., less than 3 Volts, is applied to top electrodes 30 anti the top electrodes 30 affects the necessary actuation voltage such that a larger clearance necessitates a greater actuation voltage. When the pad 17 is in the excited position (contacts open), RF signals flow unimpeded from the input port 16a to the output port 16b through signal line 16, as shown by the arrows, with only a negligible loss to the signal. In a preferred embodiment, this position corresponds to the switch on state. Thus, unlike known switches, the present switch is on when electrical contact is disengaged. In addition, since the actuation voltage is small, the present invention operates in either a normally on or in a normally off mode by applying DC voltage to either side of an actuation pad. The switching operation can be realized by applying two out-of-phase pulses at the top and bottom

Now referring to FIGS. 7A-7K, shown is a multi-level process for constructing hinge type RF MEMS switches.

5

Preferably, the temperatures for the fabrication process are controlled to be not higher than 300 degrees centigrade (C), to allow the integration compatibility of the current MMIC process. First, in FIG. 7A coplanar waveguides, i.e., ground planes 12 and signal lines 16, are defined and a first layer of 5 metal 34, for example gold, is evaporated on the coplanar waveguides. FIG. 7B shows a thin dielectric layer 36 deposited. VIA holes 38 are opened, as in FIG. 7C.

A first polyimide layer **40** is spun-on and cured as shown in FIG. **7D**, and a third layer of metal **42** is added, as in FIG. **7E**. A metal pad is formed as in FIG. **7F**, after which exposed portions of the layer **42** are evaporated. In FIGS. **7G** and **7H**, a second layer of polyimide **44** is spun-on and the post areas **46** are defined for the dielectric suspensions **32** of the top electrodes **30** and for hinge structures. Then a thick dielectric layer is grown by PECVD to define the dielectric suspensions **32**, as shown in FIG. **7I**. FIG. **7J** shows a third metal layer evaporated to form the hinge brackets **22** and top electrodes **30**. Finally, FIG. **7K** shows the polyimides etched away to release the whole structure of the present switch. The approximate processing time for sacrificial layer removal is controlled to be within about two hours or less.

Referring now to FIGS. **8A** and **8B**, various parameters are considered in the layout design which lead to the dimensions of the device. Artisans will appreciate that the device is not limited to a rectangular shape, but can be any geometry including a polygon, circle, or ellipse. Since the switch is designed for capacitive coupling operations as well as direct connections, the capacitance should be as large as possible to allow a switch down state. Thus, a contact area of the signal line **16** and metal pad **17** should be as large as possible to gain a wider operation bandwidth and lower impedance at high frequency regime.

A width of the metal pad 17 can overlap a width of the signal line 16. However, large overlap areas cause greater insertion loss in the switch up state. It is noted that coplanar waveguide characteristics with a signal line width of $20~\mu m$, $50~\mu m$, and $100~\mu m$ are viable (not shown). A width of the top electrodes 30 was chosen at $100~\mu m$ and $150~\mu m$. Combined with the different coplanar waveguide structures, six different impedance sets are available.

Bottom electrodes **20** are inserted on the ground planes **12** of coplanar **21** waveguides and are surrounded by the ground planes **12**. A bigger electrode requires a lower actuation voltage. The ground plane **12** should be big enough to sustain 50 Ω impedance over the coplanar waveguides. Typically, a width of the ground plane is about 300 μ m.

Referring now to FIG. **9**, a table shows expectations for the present invention compared to known cantilever and membrane type switches. Of particular interest, note that a required switching voltage is less than 3 Volts for the present invention, and 28 to 50 Volts for the known switches. Thus, it should be understood that an improved switch has been shown and described.

From the foregoing description, it should be understood that an improved microelectromechanical switch has been shown and described which has many desirable attributes and advantages. It is adapted to switch the flow of a signal based on a relaxed or stimulated position of a metal pad. Unlike known prior art, a signal flow of the present switch is off when the metal pad makes a connection and on when the connection is breached. In addition, the present switch responds to a low actuation voltage of 3 Volts or less. The invention is also easy to manufacture.

Other alterations and modifications will be apparent to those skilled in the art. Accordingly, the scope of the invention is not limited to the specific embodiments used to illustrate the principles of the invention. Instead, the scope

6

of the invention is properly determined by reference to the appended claims and any legal equivalents thereof.

What is claimed is:

- 1. A microelectromechanical switch that controls a flow of signals, the switch comprising:
 - a conductive pad responsive to an actuation voltage for controlling the flow of signals by selectively making and breaking electrical contacts between said conductive pad and at least one second conductive pad, without substantially deforming said conductive pad; and

brackets slidingly positioned with respect to said conductive pad to guide said conductive pad when said conductive pad makes and breaks contact.

- 2. The microelectromechanical switch according to claim 1, wherein said a actuation voltage is 3 Volts or less.
- 3. The microelectromechanical switch according to claim 1, wherein said conductive pad further includes access holes for said brackets to fit through to keep said conductive pad properly aligned when making and breaking contact.
- 4. A microelectromechanical switch that controls a flow of signals, the switch comprising:

waveguides including a signal line and at least one ground plane;

- a conductive pad responsive to an actuation voltage, said conductive pad electrically connecting said signal line and said ground plane when located in a relaxed position to send signals from said signal line to ground, and when actuated, allowing signals to flow through said signal line; and
- brackets for guiding said conductive pad when said conductive pad moves between said relaxed position and a stimulated position due to said actuation voltage.
- 5. The microelectromechanical switch according to claim 4, wherein said signal line includes an input port and an output port, the signal being grounded before reaching said output port when said conductive pad is in said relaxed position.
- 6. The microelectromechanical switch according to claim 4, further including top and bottom electrodes for moving said conductive pad between said relaxed and actuated positions.
- 7. The microelectromechanical switch according to claim 6, further including dielectric suspensions to support said top electrodes above said conductive pad and waveguides.
- **8**. The microelectromechanical switch according to claim **6**, wherein said bottom electrodes are positioned between said conductive pad and said ground plane to enhance contact of said conductive pad to said ground plane and said signal line.
- The microelectromechanical switch according to claim
 wherein said actuation voltage is less than or equal to 3
 Volts
- 10. The microelectromechanical switch according to claim 4, further including a dielectric layer positioned on 55 said signal line.
 - 11. The microelectromechanical switch according to claim 4, wherein said electrical connection is a capacitive connection
 - 12. The microelectromechanical switch according to claim 4, wherein said electrical connection is a physical short circuit.
 - 13. The microelectromechanical switch according to claim 5, wherein said input port is electrically connected to said output port by separating said conductive pad from said signal line.

* * * * *

UNITED STATES PATENT AND TRADEMARK OFFICE CERTIFICATE OF CORRECTION

PATENT NO. : 6,143,997

DATED

: November 7, 2000

INVENTOR(S) : Feng et al.

Page 1 of 1

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Column 1,

Line 41, delete "(excited" and insert -- excited -- therefor

Column 2,

Line 5, delete "Switches" and insert -- switches -- therefor

Column 5,

Line 42, delete "21"

Signed and Sealed this

Seventh Day of May, 2002

Attest:

Attesting Officer

JAMES E. ROGAN

Director of the United States Patent and Trademark Office